

Search Notes

Application/Control No.

10/685,473

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

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Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	122	4/3/2006	DWY
429	128	4/3/2006	DWY
429	142	4/3/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/3/2006	DWY
STN	4/3/2006	DWY